

Entrusted Items Concerning Preparation of Draft Proposals for JIS

Newly Established

Divisional Council	T i t l e	Assigned Organization	Contact
Basic Engineering	Surface chemical analysis – X-ray photoelectron spectroscopy – Description of selected instrumental performance parameters	Japanese Standards Association	A
Basic Engineering	Surface chemical analysis – Auger electron spectroscopy – Description of selected instrumental performance parameters	Japanese Standards Association	A
Basic Engineering	Surface chemical analysis - Secondary-ion mass spectrometry - Method for depth profiling of boron in silicon	Japanese Standards Association	A
Basic Engineering	Surface chemical analysis-Secondary-ion mass spectrometry- Determination of relative sensitivity factors from ion-implanted reference materials	Japanese Standards Association	A
Basic Engineering	Microbeam analysis - Electron probe microanalysis - Guidelines for qualitative point analysis by wavelength dispersive X-ray spectrometry	Japanese Standards Association	A
Electronics	Cores made of ferrite - Part 1: Generic specification	Japan Electronics and Information Technology Industries Association	C
Electronics	High frequency inductive components - Electrical characteristics and measuring methods - Part 2: Rated current of inductors for DC to DC converters	Japan Electronics and Information Technology Industries Association	C
Electronics	Surface mounting technology - Environmental and endurance test methods for surface mount solder joint - Part 1-4: Cyclic bending test	Japan Electronics and Information Technology Industries Association	C
Electronics	Printed board assemblies - Part 6: Evaluation criteria for voids in soldered joints of BGA and LGA	Japan Electronics and Information Technology Industries Association	C